


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/854,463	HANNUKSELA ET AL.	
	Examiner	Art Unit	
	Erick Rekstad	2621	

SEARCHED			
Class	Subclass	Date	Examiner
375	240.27 240.01 240.13 240.25		ER
386	117		ER
382	232		ER
348	14.01		ER
348	14.02		ER

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	240.25	5/27/2005	ER
375	240.27	11/14/2005	ER

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE: error <and> concealment <and> video	5/27/2005	ER
IEEE, ACM Digital Library, CiteSeer, Optics Information Database search for (h.263 and supplemental enhancement)	11/14/2005	ER
keyword search	7/21/2004	ER
keyword search	5/27/2005	ER
keyword search	11/14/2005	ER
keyword search	9/1/2006	ER